

Notice of References Cited	Application/Control No. 10/787,015	Applicant(s)/Patent Under Reexamination CHIN ET AL.	
	Examiner David M. Naff	Art Unit 1651	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,893,816 B1	05-2005	Beattie, Kenneth L.	435/6
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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FOREIGN PATENT DOCUMENTS

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	N					
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NON-PATENT DOCUMENTS

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